

Application No.	Applicant(s)
10/752,621	LEUNG, KA Y.
Examiner	Art Unit
Peguy JeanPierre	2819

SEARCHED					
Class	Subclass	Date	Examiner		
341	118	9/7/2004	PJP		
	120	/			
	155				
	172	/			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		<u></u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
east	9/7/2004	PJP		
differential comparator with ratiometric bias circuit				
	1	/		